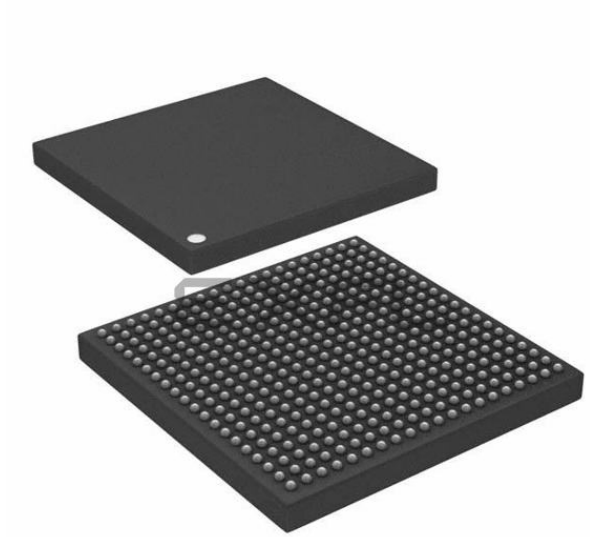

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Understanding Embedded - DSP (Digital Signal Processors)

Embedded - DSP (Digital Signal Processors) are specialized microprocessors designed to perform complex mathematical computations on digital signals in real-time. Unlike general-purpose processors, DSPs are optimized for high-speed numeric processing tasks, making them ideal for applications that require efficient and precise manipulation of digital data. These processors are fundamental in converting and processing signals in various forms, including audio, video, and communication signals, ensuring that data is accurately interpreted and utilized in embedded systems.

Applications of Embedded - DSP (Digital Signal Processors)

Details	
Product Status	Obsolete
Type	SC1400 Core
Interface	Host Interface, I²C, UART
Clock Rate	266MHz
Non-Volatile Memory	External
On-Chip RAM	400kB
Voltage - I/O	3.30V
Voltage - Core	1.20V
Operating Temperature	-40°C ~ 105°C (TJ)
Mounting Type	Surface Mount
Package / Case	400-LFBGA
Supplier Device Package	400-LFBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/msc7115vm1000

1 Pin Assignments

This section includes diagrams of the MSC7115 package ball grid array layouts and pinout allocation tables.

1.1 MAP-BGA Ball Layout Diagrams

Top and bottom views of the MAP-BGA package are shown in **Figure 2** and **Figure 3** with their ball location index numbers.

Top View

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20
A	GND	GND	DQM1	DQS2	CK	$\overline{CK}$	HD15	HD12	HD10	HD7	HD6	HD4	HD1	HD0	GND	NC	NC	NC	NC	NC
B	V_{DDM}	NC	$\overline{CS0}$	DQM2	DQS3	DQS0	CKE	$\overline{WE}$	HD14	HD11	HD8	HD5	HD2	NC	NC	NC	NC	NC	NC	NC
C	D24	D30	D25	$\overline{CS1}$	DQM3	DQM0	DQS1	$\overline{RAS}$	$\overline{CAS}$	HD13	HD9	HD3	NC	NC	NC	NC	NC	NC	NC	NC
D	V_{DDM}	D28	D27	GND	V_{DDM}	V_{DDM}	V_{DDM}	V_{DDM}	V_{DDM}	V_{DDM}	V_{DDIO}	V_{DDIO}	V_{DDIO}	V_{DDIO}	V_{DDIO}	V_{DDIO}	V_{DDC}	NC	NC	NC
E	GND	D26	D31	V_{DDM}	V_{DDM}	V_{DDC}	V_{DDC}	V_{DDC}	V_{DDC}	V_{DDM}	V_{DDIO}	V_{DDIO}	V_{DDIO}	V_{DDIO}	V_{DDIO}	V_{DDC}	V_{DDC}	NC	NC	NC
F	V_{DDM}	D15	D29	V_{DDC}	V_{DDC}	V_{DDC}	GND	GND	GND	V_{DDM}	V_{DDM}	GND	GND	GND	V_{DDIO}	V_{DDC}	V_{DDC}	NC	NC	NC
G	GND	D13	GND	V_{DDM}	V_{DDM}	GND	GND	GND	GND	GND	GND	GND	GND	GND	V_{DDIO}	V_{DDIO}	V_{DDC}	NC	NC	NC
H	D14	D12	D11	V_{DDM}	V_{DDM}	GND	GND	GND	GND	GND	GND	GND	GND	GND	V_{DDIO}	V_{DDIO}	V_{DDC}	NC	HA2	HA1
J	D10	V_{DDM}	D9	V_{DDM}	V_{DDM}	V_{DDM}	GND	GND	GND	GND	GND	GND	GND	GND	GND	V_{DDIO}	V_{DDC}	HA3	$\overline{HACK}$	$\overline{HREQ}$
K	D0	GND	D8	V_{DDC}	V_{DDM}	GND	GND	GND	GND	GND	GND	GND	GND	GND	V_{DDIO}	V_{DDIO}	V_{DDC}	HA0	HDDS	$\overline{HDS}$
L	D1	GND	D3	V_{DDC}	V_{DDM}	GND	GND	GND	GND	GND	GND	GND	GND	V_{DDIO}	V_{DDIO}	V_{DDIO}	V_{DDC}	$\overline{HCS2}$	$\overline{HCS1}$	HRW
M	D2	V_{DDM}	D5	V_{DDM}	V_{DDM}	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	V_{DDC}	V_{DDC}	SDA	UTXD	URXD
N	D4	D6	V_{REF}	V_{DDM}	V_{DDM}	V_{DDM}	GND	GND	GND	GND	GND	GND	GND	GND	V_{DDIO}	V_{DDC}	V_{DDC}	CLKIN	SCL	V_{SSPLL}
P	D7	D17	D16	V_{DDM}	V_{DDM}	V_{DDM}	GND	GND	GND	GND	GND	GND	GND	GND	V_{DDIO}	V_{DDIO}	V_{DDC}	$\overline{PORESET}$	TPSEL	V_{DDPLL}
R	GND	D19	D18	V_{DDM}	V_{DDM}	V_{DDM}	GND	V_{DDM}	GND	V_{DDM}	GND	GND	V_{DDIO}	GND	V_{DDIO}	V_{DDIO}	V_{DDC}	TDO	EE0	TEST0
T	V_{DDM}	D20	D22	V_{DDM}	V_{DDM}	V_{DDC}	V_{DDM}	V_{DDM}	V_{DDC}	V_{DDM}	V_{DDM}	V_{DDIO}	V_{DDIO}	V_{DDIO}	V_{DDIO}	V_{DDC}	V_{DDC}	NC	TMS	$\overline{HRESET}$
U	GND	D21	D23	V_{DDM}	V_{DDC}	V_{DDC}	V_{DDC}	V_{DDC}	V_{DDC}	V_{DDC}	V_{DDC}	V_{DDC}	V_{DDC}	V_{DDC}	V_{DDC}	V_{DDC}	V_{DDC}	NC	TCK	$\overline{TRST}$
V	V_{DDM}	NC	A13	A11	A10	A5	A2	BA0	NC	EVNT0	EVNT4	T0TCK	T1RFS	T1TD	T2RD	T2TD	GPIA22	GPIA24	NC	TDI
W	GND	V_{DDM}	A12	A8	A7	A6	A3	NC	EVNT1	EVNT2	T0RFS	T0TFS	T1RD	T1TFS	T2RFS	T2TFS	GPIA19	GPIA23	GPIA26	H8BIT
Y	V_{DDM}	GND	A9	A1	A0	A4	BA1	$\overline{NMI}$	EVNT3	T0RCK	T0RD	TOTD	T1RCK	T1TCK	T2RCK	T2TCK	GPIA20	GPIA21	GND	GPIA25

Figure 2. MSC7115 Molded Array Process-Ball Grid Array (MAP-BGA), Top View

1.2 Signal List By Ball Location

Table 1 lists the signals sorted by ball number and configuration.

Table 1. MSC7115 Signals by Ball Designator

Number	Signal Names					
	End of Reset	Software Controlled			Hardware Controlled	
		GPI Enabled (Default)	Interrupt Enabled	GPO Enabled	Primary	Alternate
A1	GND					
A2	GND					
A3	DQM1					
A4	DQS2					
A5	CK					
A6	$\overline{CK}$					
A7	GPIC7			GPOC7	HD15	
A8	GPIC4			GPOC4	HD12	
A9	GPIC2			GPOC2	HD10	
A10	reserved				HD7	
A11	reserved				HD6	
A12	reserved				HD4	
A13	reserved				HD1	
A14	reserved				HD0	
A15	GND					
A16 (1L44X)	NC					
A16 (1M88B)	BM3	GPID8		GPOD7	reserved	
A17	NC					
A18	NC					
A19	NC					
A20	NC					
B1	V_{DDM}					
B2	NC					
B3	$\overline{CS0}$					
B4	DQM2					
B5	DQS3					
B6	DQS0					
B7	CKE					
B8	$\overline{WE}$					
B9	GPIC6			GPOC6	HD14	
B10	GPIC3			GPOC3	HD11	
B11	GPIC0			GPOC0	HD8	
B12	reserved				HD5	
B13	reserved				HD2	
B14	NC					
B15 (1L44X)	NC					

Table 1. MSC7115 Signals by Ball Designator (continued)

Number	Signal Names					
	End of Reset	Software Controlled			Hardware Controlled	
		GPI Enabled (Default)	Interrupt Enabled	GPO Enabled	Primary	Alternate
D13	V_{DDIO}					
D14	V_{DDIO}					
D15	V_{DDIO}					
D16	V_{DDIO}					
D17	V_{DDC}					
D18	NC					
D19	NC					
D20	NC					
E1	GND					
E2	D26					
E3	D31					
E4	V_{DDM}					
E5	V_{DDM}					
E6	V_{DDC}					
E7	V_{DDC}					
E8	V_{DDC}					
E9	V_{DDC}					
E10	V_{DDM}					
E11	V_{DDIO}					
E12	V_{DDIO}					
E13	V_{DDIO}					
E14	V_{DDIO}					
E15	V_{DDIO}					
E16	V_{DDC}					
E17	V_{DDC}					
E18	NC					
E19	NC					
E20	NC					
F1	V_{DDM}					
F2	D15					
F3	D29					
F4	V_{DDC}					
F5	V_{DDC}					
F6	V_{DDC}					
F7	GND					
F8	GND					
F9	GND					
F10	V_{DDM}					

Table 1. MSC7115 Signals by Ball Designator (continued)

Number	Signal Names					
	End of Reset	Software Controlled			Hardware Controlled	
		GPI Enabled (Default)	Interrupt Enabled	GPO Enabled	Primary	Alternate
F11	V_{DDM}					
F12	GND					
F13	GND					
F14	GND					
F15	V_{DDIO}					
F16	V_{DDC}					
F17	V_{DDC}					
F18	NC					
F19	NC					
F20	NC					
G1	GND					
G2	D13					
G3	GND					
G4	V_{DDM}					
G5	V_{DDM}					
G6	GND					
G7	GND					
G8	GND					
G9	GND					
G10	GND					
G11	GND					
G12	GND					
G13	GND					
G14	GND					
G15	V_{DDIO}					
G16	V_{DDIO}					
G17	V_{DDC}					
G18	NC					
G19	NC					
G20	NC					
H1	D14					
H2	D12					
H3	D11					
H4	V_{DDM}					
H5	V_{DDM}					
H6	GND					
H7	GND					
H8	GND					

Table 1. MSC7115 Signals by Ball Designator (continued)

Number	Signal Names					
	End of Reset	Software Controlled			Hardware Controlled	
		GPI Enabled (Default)	Interrupt Enabled	GPO Enabled	Primary	Alternate
K6	GND					
K7	GND					
K8	GND					
K9	GND					
K10	GND					
K11	GND					
K12	GND					
K13	GND					
K14	GND					
K15	V_{DDIO}					
K16	V_{DDIO}					
K17	V_{DDC}					
K18	reserved				HA0	
K19	reserved				HDDS	
K20	reserved				$\overline{\text{HDS}}$/HDS or $\overline{\text{HWR}}$/HWR	
L1	D1					
L2	GND					
L3	D3					
L4	V_{DDC}					
L5	V_{DDM}					
L6	GND					
L7	GND					
L8	GND					
L9	GND					
L10	GND					
L11	GND					
L12	GND					
L13	GND					
L14	V_{DDIO}					
L15	V_{DDIO}					
L16	V_{DDIO}					
L17	V_{DDC}					
L18 (1L44X)	reserved				$\overline{\text{HCS2}}$/HCS2	
L18 (1M88B)	GPIB11			GPOB11	$\overline{\text{HCS2}}$/HCS2	
L19	reserved				$\overline{\text{HCS1}}$/HCS1	
L20	reserved				HRW or $\overline{\text{HRD}}$/HRD	
M1	D2					
M2	V_{DDM}					

Table 1. MSC7115 Signals by Ball Designator (continued)

Number	Signal Names					
	End of Reset	Software Controlled			Hardware Controlled	
		GPI Enabled (Default)	Interrupt Enabled	GPO Enabled	Primary	Alternate
P1	D7					
P2	D17					
P3	D16					
P4	V_{DDM}					
P5	V_{DDM}					
P6	V_{DDM}					
P7	GND					
P8	GND					
P9	GND					
P10	GND					
P11	GND					
P12	GND					
P13	GND					
P14	GND					
P15	V_{DDIO}					
P16	V_{DDIO}					
P17	V_{DDC}					
P18	$\overline{\text{PORESET}}$					
P19	TPSEL					
P20	V_{DDPLL}					
R1	GND					
R2	D19					
R3	D18					
R4	V_{DDM}					
R5	V_{DDM}					
R6	V_{DDM}					
R7	GND					
R8	V_{DDM}					
R9	GND					
R10	V_{DDM}					
R11	GND					
R12	GND					
R13	V_{DDIO}					
R14	GND					
R15	V_{DDIO}					
R16	V_{DDIO}					
R17	V_{DDC}					
R18	TDO					

Table 1. MSC7115 Signals by Ball Designator (continued)

Number	Signal Names					
	End of Reset	Software Controlled			Hardware Controlled	
		GPI Enabled (Default)	Interrupt Enabled	GPO Enabled	Primary	Alternate
U17	V_{DDC}					
U18	NC					
U19	TCK					
U20	$\overline{\text{TRST}}$					
V1	V_{DDM}					
V2	NC					
V3	A13					
V4	A11					
V5	A10					
V6	A5					
V7	A2					
V8	BA0					
V9	NC					
V10	reserved				EVNT0	
V11	SWTE	GPIA16	$\overline{\text{IRQ12}}$	GPOA16	EVNT4	
V12	GPIA8		$\overline{\text{IRQ6}}$	GPOA8	T0TCK	
V13	GPIA4		$\overline{\text{IRQ1}}$	GPOA4	T1RFS	
V14	GPIA0		$\overline{\text{IRQ11}}$	GPOA0	T1TD	
V15	GPIA28		$\overline{\text{IRQ17}}$	GPOA28	reserved	T2RD
V16	GPID6			GPOD6	reserved	T2TD
V17	GPIA22		$\overline{\text{IRQ22}}$	GPOA22	reserved	
V18	GPIA24		$\overline{\text{IRQ24}}$	GPOA24	reserved	
V19	NC					
V20	TDI					
W1	GND					
W2	V_{DDM}					
W3	A12					
W4	A8					
W5	A7					
W6	A6					
W7	A3					
W8	NC					
W9	GPIA17		$\overline{\text{IRQ13}}$	GPOA17	EVNT1	CLKO
W10	BM0	GPIC14		GPOC14	EVNT2	
W11	GPIA10		$\overline{\text{IRQ5}}$	GPOA10	T0RFS	
W12	GPIA7		$\overline{\text{IRQ7}}$	GPOA7	T0TFS	
W13	GPIA3		$\overline{\text{IRQ8}}$	GPOA3	T1RD	
W14	GPIA1		$\overline{\text{IRQ10}}$	GPOA1	T1TFS	

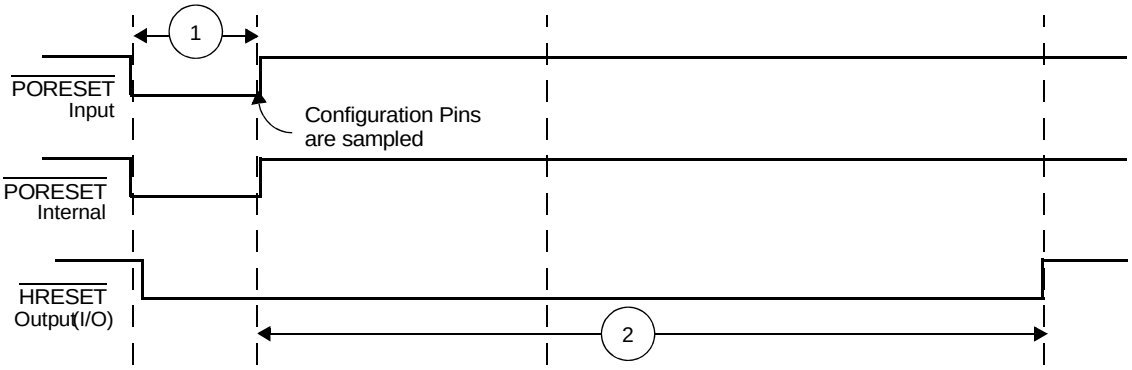


Figure 4. Timing Diagram for a Reset Configuration Write

2.5.4 DDR DRAM Controller Timing

This section provides the AC electrical characteristics for the DDR DRAM interface.

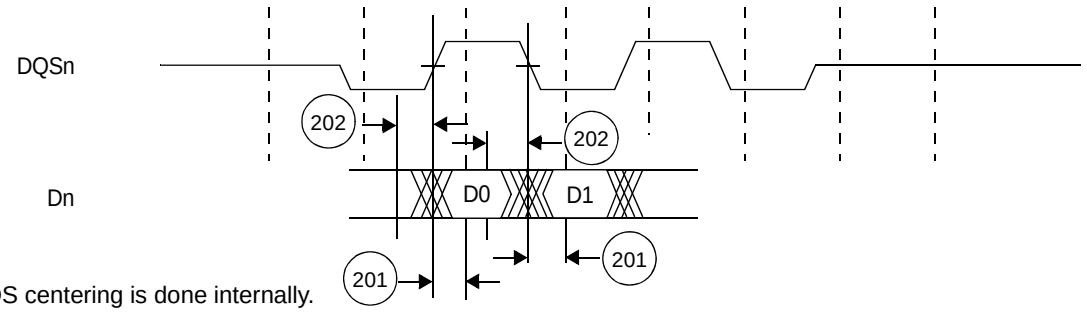
2.5.4.1 DDR DRAM Input AC Timing Specifications

Table 18 provides the input AC timing specifications for the DDR DRAM interface.

Table 18. DDR DRAM Input AC Timing

No.	Parameter	Symbol	Min	Max		Unit
				Mask Set 1L44X	Mask Set 1M88B	
—	AC input low voltage	V_{IL}	—	V_{REF} – 0.31	V_{REF} – 0.31	V
—	AC input high voltage	V_{IH}	V_{REF} + 0.31	V_{DDM} + 0.3	V_{DDM} + 0.3	V
201	Maximum Dn input setup skew relative to DQSn input	—	—	1026	900	ps
202	Maximum Dn input hold skew relative to DQSn input	—	—	386	900	ps

Notes:
1. Maximum possible skew between a data strobe (DQSn) and any corresponding bit of data (D[8n + {0...7}] if 0 ≤ n ≤ 7).
2. See **Table 19** for t_{CK} value.
3. Dn should be driven at the same time as DQSn. This is necessary because the DQSn centering on the DQn data tenure is done internally.



Note: DQS centering is done internally.

Figure 5. DDR DRAM Input Timing Diagram

Figure 6 shows the DDR DRAM output timing diagram.

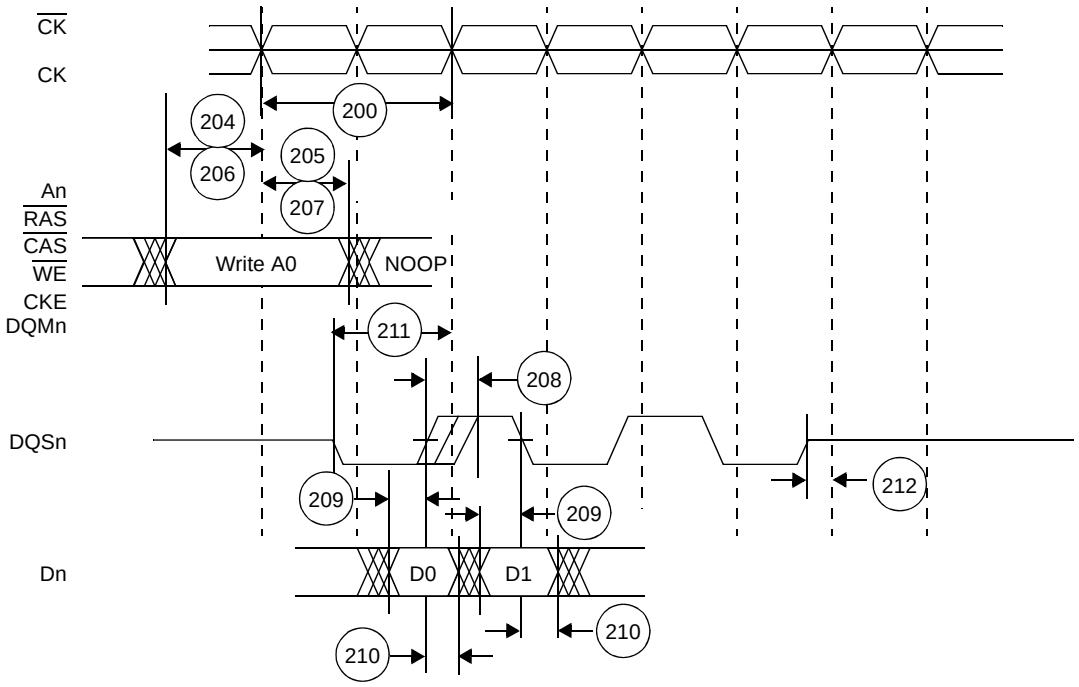


Figure 6. DDR DRAM Output Timing Diagram

Figure 7 provides the AC test load for the DDR DRAM bus.

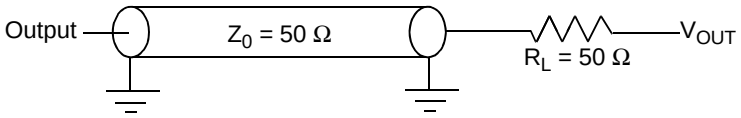


Figure 7. DDR DRAM AC Test Load

Table 20. DDR DRAM Measurement Conditions

Symbol	DDR DRAM	Unit
V_{TH}[1]	V_{REF} ± 0.31 V	V
V_{OUT}[2]	0.5 × V_{DDM}	V

Notes: **1.** Data input threshold measurement point.
2. Data output measurement point.

2.5.5 TDM Timing

Table 21. TDM Timing

No.	Characteristic	Expression	Min	Max	Units
300	TDMxRCK/TDMxTCK	TC	20.0	—	ns
301	TDMxRCK/TDMxTCK High Pulse Width	0.4 × TC	8.0	—	ns
302	TDMxRCK/TDMxTCK Low Pulse Width	0.4 × TC	8.0	—	ns
303	TDM all input Setup time		3.0	—	ns
304	TDMxRD Hold time		3.5	—	ns
305	TDMxTFS/TDMxRFS input Hold time		2.0	—	ns
306	TDMxTCK High to TDMxTD output active		4.0	—	ns

2.5.6 HDI16 Signals

Table 22. Host Interface (HDI16) Timing[1, 2]

No.	Characteristics[3]	Mask Set 1L44X		Mask Set 1M88B		Unit
		Expression	Value	Expression	Value	
40	Host Interface Clock period	T_{HCLK}	Note 1	T_{CORE}	Note 1	ns
44a	Read data strobe minimum assertion width[4] HACK read minimum assertion width	$3.0 \times T_{HCLK}$	Note 11	$2.0 \times T_{CORE} + 9.0$	Note 11	ns
44b	Read data strobe minimum deassertion width[4] HACK read minimum deassertion width	$1.5 \times T_{HCLK}$	Note 11	$1.5 \times T_{CORE}$	Note 11	ns
44c	Read data strobe minimum deassertion width[4] after “Last Data Register” reads[5,6], or between two consecutive CVR, ICR, or ISR reads[7] HACK minimum deassertion width after “Last Data Register” reads[5,6]	$2.5 \times T_{HCLK}$	Note 11	$2.5 \times T_{CORE}$	Note 11	ns
45	Write data strobe minimum assertion width[8] HACK write minimum assertion width	$1.5 \times T_{HCLK}$	Note 11	$1.5 \times T_{CORE}$	Note 11	ns
46	Write data strobe minimum deassertion width[8] HACK write minimum deassertion width after ICR, CVR and Data Register writes[5]	$2.5 \times T_{HCLK}$	Note 11	$2.5 \times T_{CORE}$	Note 11	ns
47	Host data input minimum setup time before write data strobe deassertion[8] Host data input minimum setup time before HACK write deassertion	—	3.0	—	2.5	ns
48	Host data input minimum hold time after write data strobe deassertion[8] Host data input minimum hold time after HACK write deassertion	—	4.0	—	2.5	ns
49	Read data strobe minimum assertion to output data active from high impedance[4] HACK read minimum assertion to output data active from high impedance	—	1.0	—	1.0	ns
50	Read data strobe maximum assertion to output data valid[4] HACK read maximum assertion to output data valid	$(2.0 \times T_{HCLK}) + 8.0$	Note 11	$(2.0 \times T_{CORE}) + 8.0$	Note 11	ns
51	Read data strobe maximum deassertion to output data high impedance[4] HACK read maximum deassertion to output data high impedance	—	8.0	—	9.0	ns
52	Output data minimum hold time after read data strobe deassertion[4] Output data minimum hold time after HACK read deassertion	—	1.0	—	1.0	ns
53	HCS[1–2] minimum assertion to read data strobe assertion[4]	—	0.0	—	0.5	ns
54	HCS[1–2] minimum assertion to write data strobe assertion[8]	—	0.0	—	0.0	ns
55	HCS[1–2] maximum assertion to output data valid	$(2.0 \times T_{HCLK}) + 8.0$	Note 11	$(2.0 \times T_{CORE}) + 6.0$	Note 11	ns
56	HCS[1–2] minimum hold time after data strobe deassertion[9]	—	0.0	—	0.5	ns
57	HA[0–3], HRW minimum setup time before data strobe assertion[9]	—	5.0	—	5.0	ns
58	HA[0–3], HRW minimum hold time after data strobe deassertion[9]	—	5.0	—	5.0	ns
61	Maximum delay from read data strobe deassertion to host request deassertion for “Last Data Register” read[4, 5, 10]	$(3.0 \times T_{HCLK}) + 8.0$	Note 11	$(3.0 \times T_{CORE}) + 6.0$	Note 11	ns
62	Maximum delay from write data strobe deassertion to host request deassertion for “Last Data Register” write[5,8,10]	$(3.0 \times T_{HCLK}) + 8.0$	Note 11	$(3.0 \times T_{CORE}) + 6.0$	Note 11	ns
63	Minimum delay from DMA HACK (OAD=0) or Read/Write data strobe(OAD=1) deassertion to HREQ assertion.	$(2.0 \times T_{HCLK}) + 1.0$	Note 11	$(2.0 \times T_{CORE}) + 1.0$	Note 11	ns
64	Maximum delay from DMA HACK (OAD=0) or Read/Write data strobe(OAD=1) assertion to HREQ deassertion	$(5.0 \times T_{HCLK}) + 8.0$	Note 11	$(5.0 \times T_{CORE}) + 6.0$	Note 11	ns

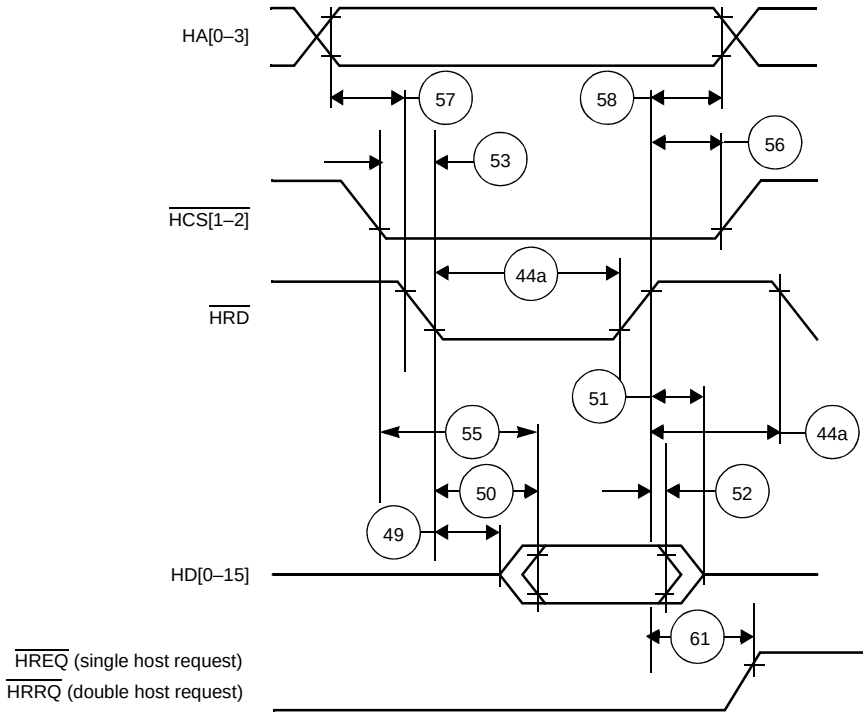


Figure 11. Read Timing Diagram, Double Data Strobe

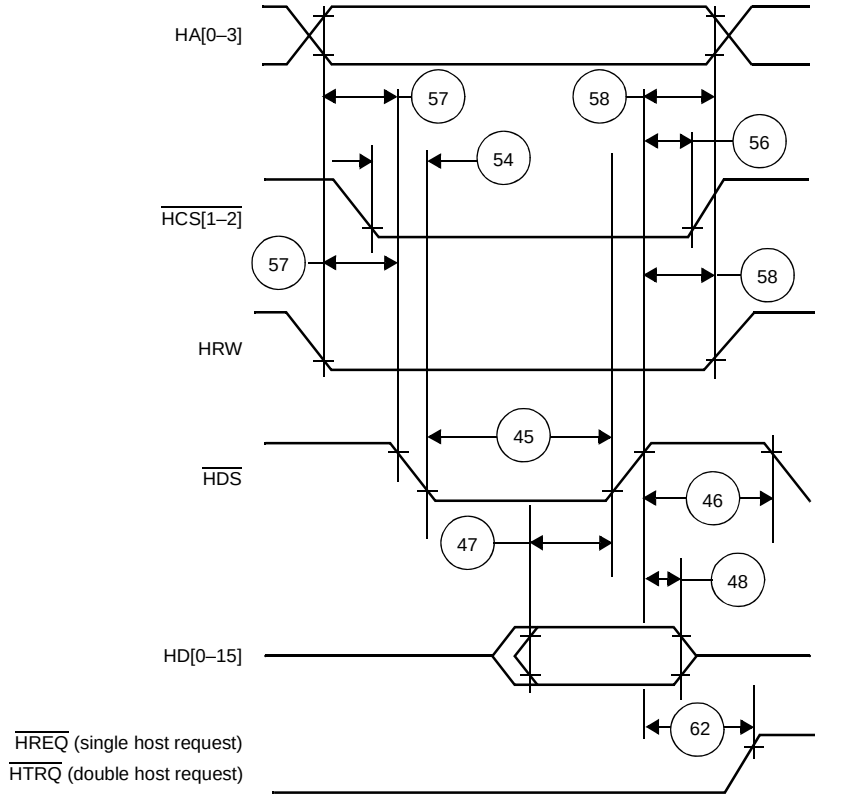


Figure 12. Write Timing Diagram, Single Data Strobe

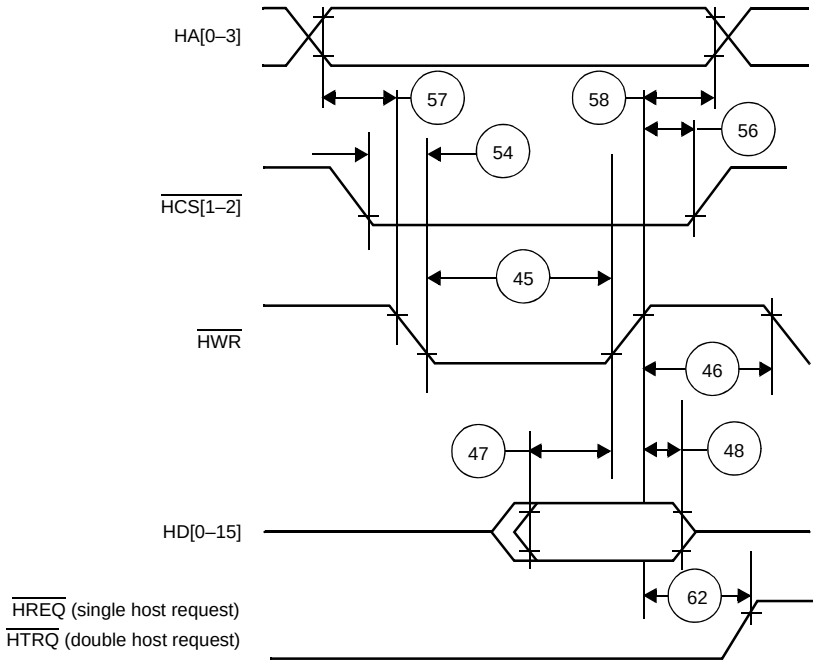


Figure 13. Write Timing Diagram, Double Data Strobe

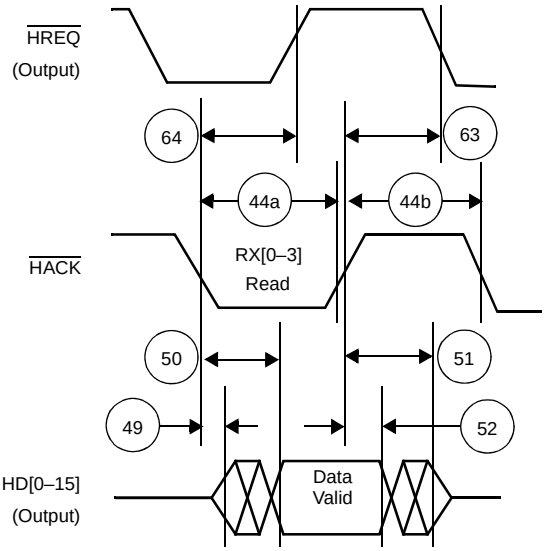


Figure 14. Host DMA Read Timing Diagram, HPCR[OAD] = 0

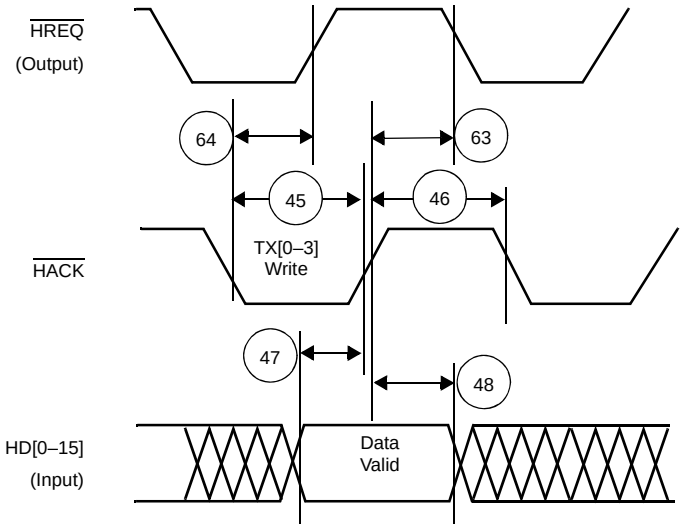


Figure 15. Host DMA Write Timing Diagram, HPCR[OAD] = 0

2.5.12 JTAG Signals

Table 28. JTAG Timing

No.	Characteristics	All frequencies		Unit
		Min	Max	
700	TCK frequency of operation (1/($T_C \times 3$); maximum 22 MHz)	0.0	40.0	MHz
701	TCK cycle time	25.0	—	ns
702	TCK clock pulse width measured at V_M = 1.6 V	11.0	—	ns
703	TCK rise and fall times	0.0	3.0	ns
704	Boundary scan input data set-up time	5.0	—	ns
705	Boundary scan input data hold time	14.0	—	ns
706	TCK low to output data valid	0.0	20.0	ns
707	TCK low to output high impedance	0.0	20.0	ns
708	TMS, TDI data set-up time	5.0	—	ns
709	TMS, TDI data hold time	25.0	—	ns
710	TCK low to TDO data valid	0.0	24.0	ns
711	TCK low to TDO high impedance	0.0	10.0	ns
712	$\overline{\text{TRST}}$ assert time	100.0	—	ns

Note: All timings apply to OCE module data transfers as the OCE module uses the JTAG port as an interface.

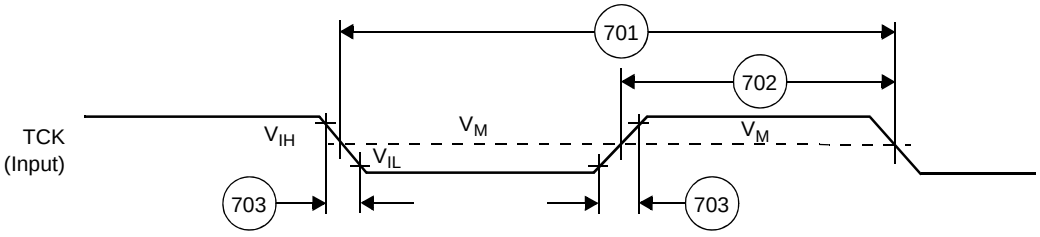


Figure 22. Test Clock Input Timing Diagram

3.2.2.2 Case 2

The power-up sequence is as follows:

1. Turn on the V_{DDIO} (3.3 V) supply first.
2. Turn on the V_{DDC} (1.2 V) and V_{DDM} (2.5 V) supplies simultaneously (second).
3. Turn on the V_{REF} (1.25 V) supply last (third).

Note: Make sure that the time interval between the ramp-up of V_{DDIO} and V_{DDC}/V_{DDM} is less than 10 ms.

The power-down sequence is as follows:

1. Turn off the V_{REF} (1.25 V) supply first.
2. Turn off the V_{DDM} (2.5 V) supply second.
3. Turn off the V_{DDC} (1.2 V) supply third.
4. Turn of the V_{DDIO} (3.3 V) supply fourth (last).

Use the following guidelines:

- Make sure that the time interval between the ramp-down for V_{DDIO} and V_{DDC} is less than 10 ms.
- Make sure that the time interval between the ramp-up or ramp-down for V_{DDC} and V_{DDM} is less than 10 ms for power-up and power-down.
- Refer to **Figure 27** for relative timing for Case 2.

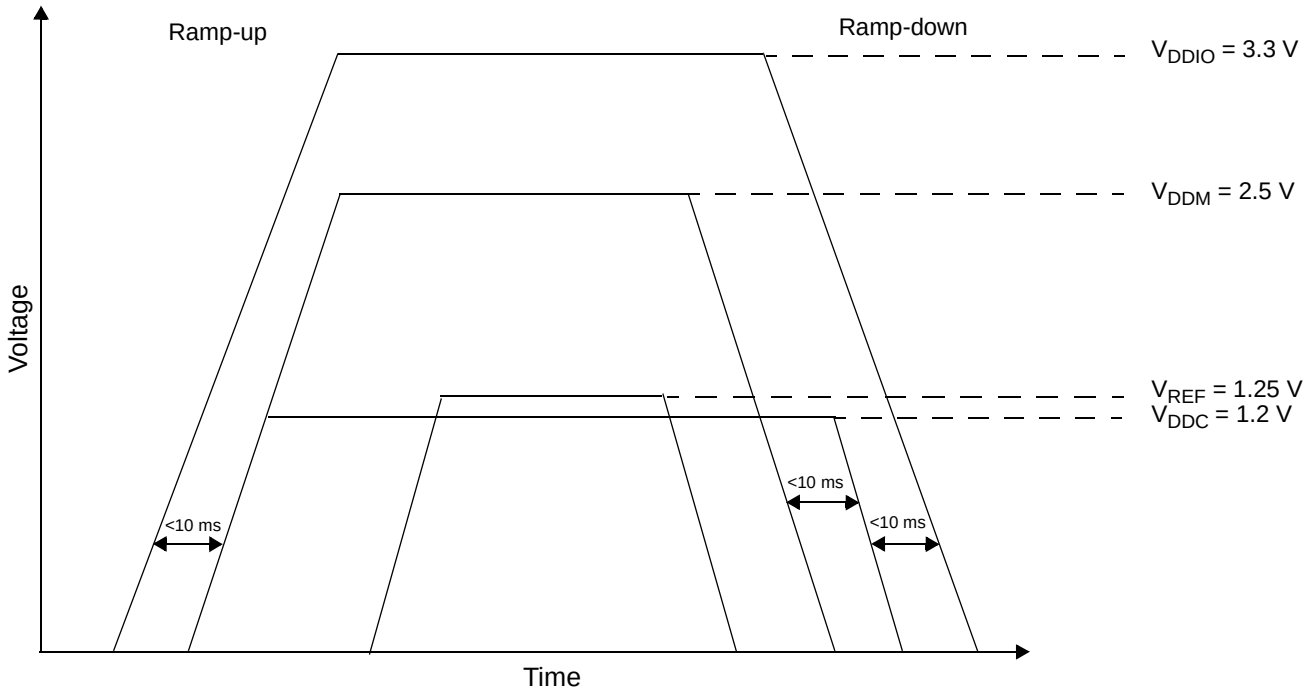


Figure 27. Voltage Sequencing Case 2

3.2.2.5 Case 5 (not recommended for new designs)

The power-up sequence is as follows:

1. Turn on the V_{DDIO} (3.3 V) supply first.
2. Turn on the V_{DDM} (2.5 V) supply second.
3. Turn on the V_{DDC} (1.2 V) supply third.
4. Turn on the V_{REF} (1.25 V) supply fourth (last).

Note: Make sure that the time interval between the ramp-up of V_{DDIO} and V_{DDM} is less than 10 ms.

The power-down sequence is as follows:

1. Turn off the V_{REF} (1.25 V) supply first.
2. Turn off the V_{DDC} (1.2 V) supply second.
3. Turn off the V_{DDM} (2.5 V) supply third.
4. Turn of the V_{DDIO} (3.3 V) supply fourth (last).

Use the following guidelines:

- Make sure that the time interval between the ramp-down of V_{DDIO} and V_{DDM} is less than 10 ms.
- Make sure that the time interval between the ramp-up or ramp-down for V_{DDC} and V_{DDM} is less than 2 ms for power-up and power-down.
- Refer to **Figure 30** for relative timing for power sequencing case 5.

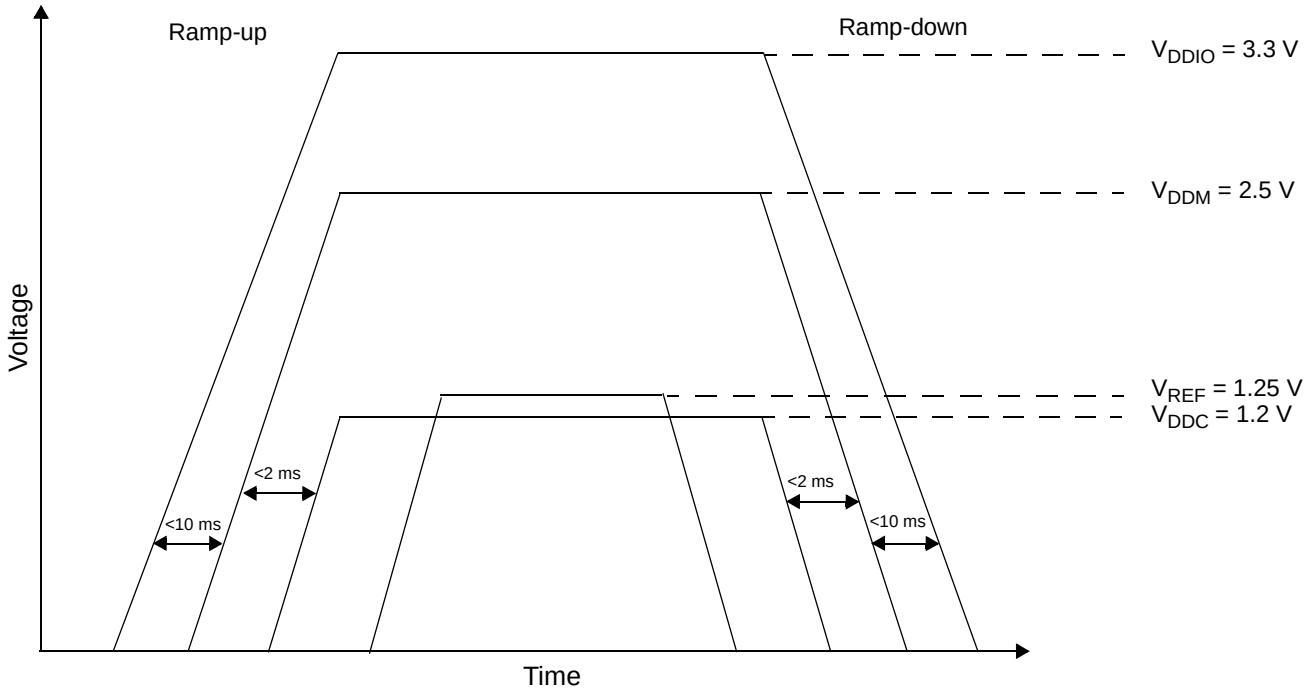


Figure 30. Voltage Sequencing Case 5

Note: Cases 1, 2, 3, and 4 are recommended for system design. Designs that use Case 5 may have large current spikes on the V_{DDM} supply at startup and is not recommended for most designs. If a design uses case 5, it must accommodate the potential current spikes. Verify risks related to current spikes using actual information for the specific application.

3.2.7 Power Supply Design

One of the most common ways to derive power is to use either a simple fixed or adjustable linear regulator. For the system I/O voltage supply, a simple fixed 3.3 V supply can be used. However, a separate adjustable linear regulator supply for the core voltage V_{DDC} should be implemented. For the memory power supply, regulators are available that take care of all DDR power requirements.

Table 30. Recommended Power Supply Ratings

Supply	Symbol	Nominal Voltage	Current Rating
Core	V_{DDC}	1.2 V	1.5 A per device
Memory	V_{DDM}	2.5 V	0.5 A per device
Reference	V_{REF}	1.25 V	10 µA per device
I/O	V_{DDIO}	3.3 V	1.0 A per device

3.3 Estimated Power Usage Calculations

The following equations permit estimated power usage to be calculated for individual design conditions. Overall power is derived by totaling the power used by each of the major subsystems:

$$P_{TOTAL} = P_{CORE} + P_{PERIPHERALS} + P_{DDRIO} + P_{IO} + P_{LEAKAGE} \quad \textit{Eqn. 3}$$

This equation combines dynamic and static power. Dynamic power is determined using the generic equation:

$$C \times V^2 \times F \times 10^{-3}\ mW \quad \textit{Eqn. 4}$$

where,

C = load capacitance in pF

V = peak-to-peak voltage swing in V

F = frequency in MHz

3.3.1 Core Power

Estimation of core power is straightforward. It uses the generic dynamic power equation and assumes that the core load capacitance is 750 pF, core voltage swing is 1.2 V, and the core frequency is 200 MHz or 266 MHz. This yields:

$$P_{CORE} = 750\ pF \times (1.2\ V)^2 \times 200\ MHz \times 10^{-3} = 216\ mW \quad \textit{Eqn. 5}$$

$$P_{CORE} = 750\ pF \times (1.2\ V)^2 \times 266\ MHz \times 10^{-3} = 287\ mW \quad \textit{Eqn. 6}$$

This equation allows for adjustments to voltage and frequency if necessary.

3.3.4 External I/O Power

The estimation of the I/O power is similar to the computation of the peripheral power estimates. The power consumption per signal line is computed assuming a maximum load of 20 pF, a voltage swing of 3.3 V, and a switching frequency of 25 MHz or 33 MHz, which yields:

$$P_{IO} = 20\ pF \times (3.3\ V)^2 \times 25\ MHz \times 10^{-3} = 5.44\ mW\ per\ I/O\ line \quad \text{Eqn. 16}$$

$$P_{IO} = 20\ pF \times (3.3\ V)^2 \times 33\ MHz \times 10^{-3} = 7.19\ mW\ per\ I/O\ line \quad \text{Eqn. 17}$$

Multiply this number by the number of I/O signal lines used in the application design to compute the total I/O power.

Note: The signal loading depends on the board routing. For systems using a single DDR device, the load could be as low as 7 pF.

3.3.5 Leakage Power

The leakage power is for all power supplies combined at a specific temperature. The value is temperature dependent. The observed leakage value at room temperature is 64 mW.

3.3.6 Example Total Power Consumption

Using the examples in this section and assuming four peripherals and 10 I/O lines active, a total power consumption value is estimated as the following:

$$P_{TOTAL}\ (200\ MHz\ core) = 216 + (4 \times 2.88) + 324{,}2 + (10 \times 5.44) + 64 = 670.12\ mW \quad \text{Eqn. 18}$$

$$P_{TOTAL}\ (266\ MHz\ core) = 287 + (4 \times 3.83) + 326.3 + (10 \times 7.19) + 64 = 764.52\ mW \quad \text{Eqn. 19}$$

3.4 Reset and Boot

This section describes the recommendations for configuring the MSC7115 at reset and boot.

3.4.1 Reset Circuit

$\overline{\text{HRESET}}$ is a bidirectional signal and, if driven as an input, should be driven with an open collector or open-drain device. For an open-drain output such as $\overline{\text{HRESET}}$, take care when driving many buffers that implement input bus-hold circuitry. The bus-hold currents can cause enough voltage drop across the pull-up resistor to change the logic level to low. Either a smaller value of pull-up or less current loading from the bus-hold drivers overcomes this issue. To avoid exceeding the MSC7115 output current, the pull-up value should not be too small (a 1 KΩ pull-up resistor is used in the MSC711xADS reference design).

3.6 Connectivity Guidelines

This section summarizes the connections and special conditions, such as pull-up or pull-down resistors, for the MSC7115 device. Following are guidelines for signal groups and configuration settings:

- *Clock and reset signals*.
  - SWTE is used to configure the MSC7115 device and is sampled on the deassertion of $\overline{\text{PORESET}}$, so it should be tied to V_{DDC} or GND either directly or through pull-up or pull-down resistors until $\overline{\text{PORESET}}$ is deasserted. After $\overline{\text{PORESET}}$, this signal can be left floating.
  - BM[0–1] configure the MSC7115 device and are sampled until $\overline{\text{PORESET}}$ is deasserted, so they should be tied to V_{DDIO} or GND either directly or through pull-up or pull-down resistors.
  - $\overline{\text{HRESET}}$ should be pulled up.
- *Interrupt signals*. When used, $\overline{\text{IRQ}}$ pins must be pulled up.
- *HDI16 signals*.
  - When they are configured for open-drain, the $\overline{\text{HREQ}}$/HREQ or $\overline{\text{HTRQ}}$/HTRQ signals require a pull-up resistor. However, these pins are also sampled at power-on reset to determine the HDI16 boot mode and may need to be pulled down. When these pins must be pulled down on reset and pulled up otherwise, a buffer can be used with the $\overline{\text{HRESET}}$ signal as the enable.
  - When the device boots through the HDI16, the HDDS, HDSP and H8BIT pins should be pulled up or down, depending on the required boot mode settings.
- *I^2C signals*. The SCL and SDA signals, when programmed for I^2C, requires an external pull-up resistor.
- *General-purpose I/O (GPIO) signals*. An unused GPIO pin can be disconnected. After boot, program it as an output pin.
- Other signals.
  - The $\overline{\text{TEST0}}$ pin must be connected to ground.
  - The $\overline{\text{TPSEL}}$ pin should be pulled up to enable debug access via the EOnCE port and pulled down for boundary scan.
  - Pins labelled NO CONNECT (NC) must not be connected.
  - When a 16-pin double data rate (DDR) interface is used, the 16 unused data pins should be no connects (floating) if the used lines are terminated.
  - Do not connect DBREQ to DONE (as you would for the MSC8101 device). Connect DONE to one of the EVNT pins, and DBREQ to HRRQ.

4 Ordering Information

Consult a Freescale Semiconductor sales office or authorized distributor to determine product availability and place an order.

Part	Supply Voltage	Package Type	Pin Count	Core Frequency (MHz)	Solder Spheres	Order Number
MSC7115 (mask 1L44X	1.2 V core 2.5 V mem. 3.3 V I/O	Molded Array Process-Ball Grid Array (MAP-BGA)	400	200	Lead-free	MSC7115VM800
					Lead-bearing	MSC7115VF800
MSC7115 (mask 1M88B)	1.2 V core 2.5 V mem 3.3 V I/O	Molded Array Process-Ball Grid Array (MAP-BGA)	400	266	Lead-free	MSC7115VM1000
					Lead-bearing	MSC7115VF1000

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